

**Advanced N-Ch Power MOSFET** 

### SWITCHING REGULATOR APPLICATIONS

### **Features**

• High Voltage: BV<sub>DSS</sub>=600V(Min.)

• Low  $C_{rss}$ :  $C_{rss}$ =9.7pF(Typ.)

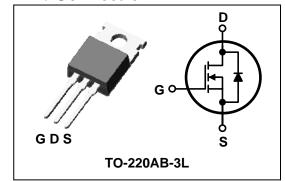
• Low gate charge : Qg=22nC(Typ.)

• Low  $R_{DS(on)}:R_{DS(on)}=1.2\Omega(Max.)$ 

## **Ordering Information**

Type No.	Marking	Package Code
SMK0860P	SMK0860	TO-220AB-3L

### **PIN Connection**



## Absolute maximum ratings ( $T_C$ =25°C unless otherwise noted)

Characteristic		j	Symbol	Ratin	ıg	Uni	t		
Drain-source voltage		$V_{DSS}$		600		V			
Gate-source voltage			$V_{GSS}$	±30		V			
Drain current (DC) *		т	(Tc=25℃)	7.5		А			
		$\mathbf{I}_{D}$	(Tc=100°C)	4.7		А			
Drain current (Pulsed) *			$I_{DM}$	30		А			
Drain power dissipation			$P_D$	90		W			
Avalanche current (Single)	2	I <sub>AS</sub>		7.5		А			
Single pulsed avalanche energy	2		E <sub>AS</sub>	325		mJ			
Avalanche current (Repetitive)	1		${ m I}_{\sf AR}$	7.5		А			
Repetitive avalanche energy	1	E <sub>AR</sub>		E <sub>AR</sub>		21.7	1	mJ	
Junction temperature		T <sub>J</sub>		150		°C			
Storage temperature range			$T_{stg}$	-55~1	50	Ų			

<sup>\*</sup> Limited by maximum junction temperature

Cha	racteristic	Symbol	Typ.	Max	Unit
Thermal	Junction-case	$R_{th(\mathtt{J-C})}$	ı	1.38	°C/W
resistance	Junction-ambient	$R_{th(J-a)}$	ı	62.5	C/ VV

## $\boldsymbol{Electrical\ Characteristics}\ (T_{C}\text{=}25^{\circ}C\ unless\ otherwise\ noted})$

Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Drain-source breakdown voltage	$BV_{DSS}$	$I_D = 250 \mu A, V_{GS} = 0$	600	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D=250\mu A$ , $V_{DS}=V_{GS}$	2.0	-	4.0	V
Drain-source cut-off current	$I_{DSS}$	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	-	-	1	μΑ
Gate leakage current	$I_{GSS}$	$V_{DS}$ =0V, $V_{GS}$ =±30V	1	1	±100	nA
Drain-source on-resistance 4	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =3.75A	-	1.0	1.2	Ω
Forward transfer conductance 4	g <sub>fs</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> =3.75A	-	7.3	-	S
Input capacitance	Ciss	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V	-	968	1210	
Output capacitance	Coss	f=1MHz	-	105	131	pF
Reverse transfer capacitance	Crss		-	9.7	12.1	
Turn-on delay time	t <sub>d(on)</sub>		-	18	-	
Rise time	t <sub>r</sub>	$V_{DD}$ =300V, $I_{D}$ =7.5A $R_{G}$ =25 $\Omega$	-	19	-	nc
Turn-off delay time	t <sub>d(off)</sub>	34	-	72	-	ns
Fall time	t <sub>f</sub>		-	28	-	
Total gate charge	$Q_g$	V <sub>DS</sub> =480V, V <sub>GS</sub> =10V	-	22	27	
Gate-source charge	$Q_{gs}$	I <sub>D</sub> =7.5A	-	5.2	-	nC
Gate-drain charge	$Q_{gd}$	34	-	6.3	-	

## Source-Drain Diode Ratings and Characteristics ( $T_C$ =25°C unless otherwise noted)

Characteristic	Symbol	Test Condition	Min	Тур	Max	Unit
Source current (DC)	I <sub>S</sub>	Integral reverse diode	-	-	7.5	Α
Source current (Pulsed) 1	$I_{SM}$	in the MOSFET		-	30	A
Forward voltage 4	$V_{SD}$	$V_{GS}$ =0V, $I_{S}$ =7.5A	-	-	1.4	V
Reverse recovery time	t <sub>rr</sub>	I <sub>s</sub> =7.5A, V <sub>GS</sub> =0,	-	365	-	ns
Reverse recovery charge	Q <sub>rr</sub>	di <sub>S</sub> /dt=100A/us	-	3.4	-	uC

#### Note;

① Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

② L=10.6mH,  $I_{AS}$ =7.5A,  $V_{DD}$ =50V,  $R_{G}$ =27 $\Omega$ 

③ Pulse Test : Pulse Width < 300us, Duty cycle ≤ 2%

4 Essentially independent of operating temperature

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## **Electrical Characteristic Curves**

Fig. 1  $I_D$  -  $V_{DS}$ 

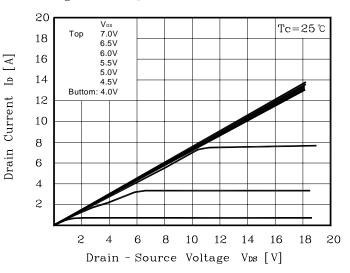


Fig. 2  $I_D\,$  -  $\,V_{GS}\,$ 

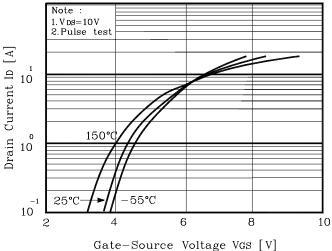


Fig. 3  $R_{DS(on)}$  -  $I_D$ 

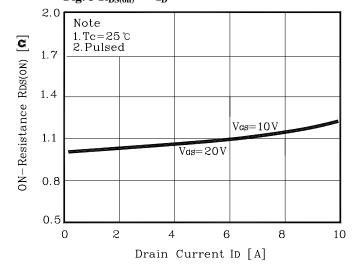


Fig. 4  $I_S$  -  $V_{SD}$ 

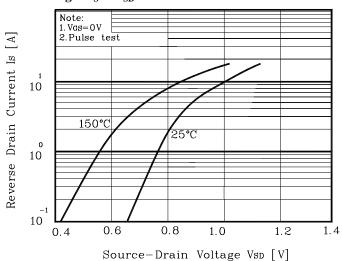


Fig. 5 Capacitance -  $V_{DS}$ 

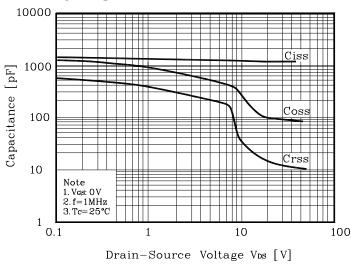
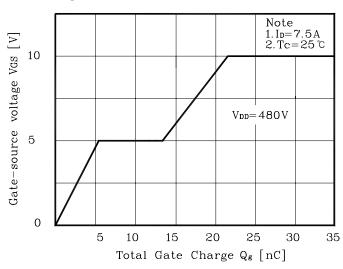
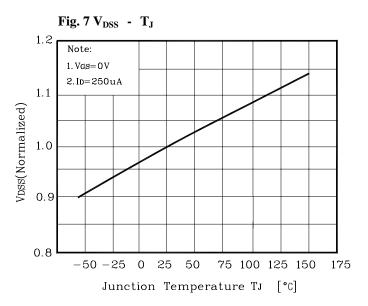


Fig.6  $V_{GS}$  -  $Q_{G}$ 



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### **Electrical Characteristic Curves**



3.0 Note:
1. Vas=10V
2.1p=3.75A

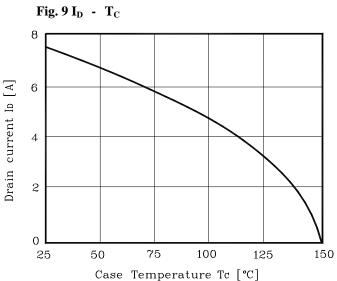
1.5

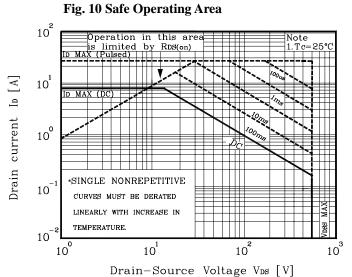
0.0

-50 -25 0 25 50 75 100 125 150 175

Junction Temperature TJ [°C]

Fig.8  $R_{DS(on)}$  -  $T_J$ 





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Fig. 10 Gate Charge Test Circuit & Waveform

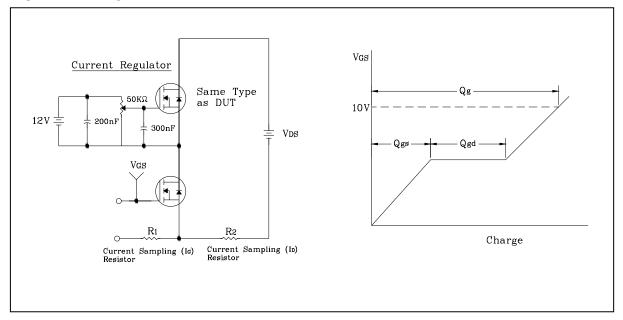


Fig. 11 Resistive Switching Test Circuit & Waveform

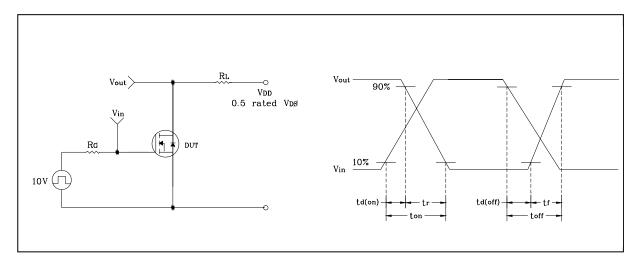
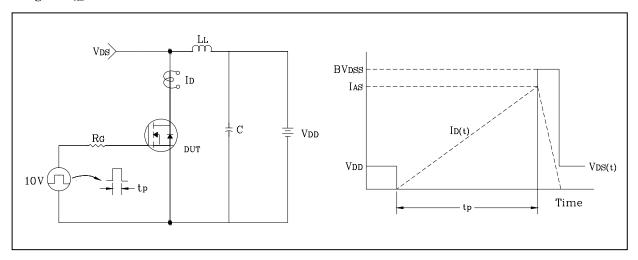
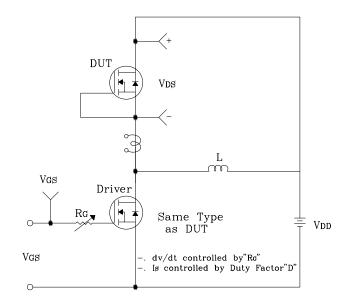


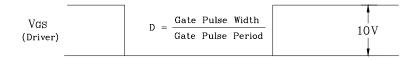
Fig. 12  $E_{AS}$  Test Circuit & Waveform

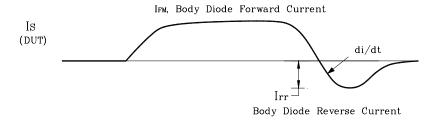


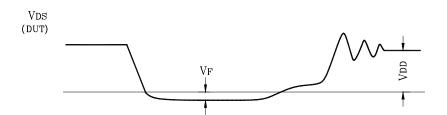
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Fig. 13 Diode Reverse Recovery Time Test Circuit & Waveform

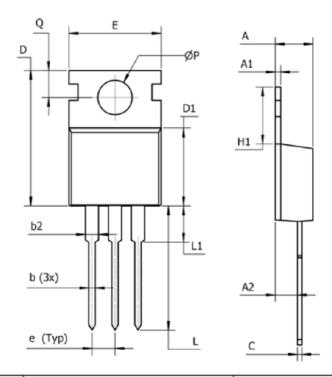








## **Outline Dimension**



DIM	ММ	INCHES		
D	14.22-16.51	0.560-0.650		
ØP	Ø3.53-4.09	Ø0.139-0.161		
H1	5.84-6.86	0.230-0.270		
b	0.38-1.02	0.015-0.040		
b2	1.14-1.78	0.045-0.070		
D1	8.38-9.02	0.330-0.355		
е	2.54	0.100		
E	9.65-10.67	0.380-0.420		
L1	6.35(MAX)	0.250(MAX)		
А	3.56-4.83	0.140-0.190		
A1	0.51-0.71	0.020-0.028		
L	12.70-14.73	0.500-0.580		
A2	2.03-2.92	0.080-0.115		
Q	2.54-3.43	0.100-0.135		
С	0.36-0.61	0.014-0.024		

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